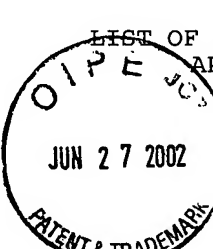


FORM PTO-1449		Atty. Docket No.: R11.12-0763	Appl. No.: 10/046,647
 <p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p>		First Named Inventor:	
		Eric R. Lovegren et al.	
		Filing Date	Group Art:
		October 29, 2001	2857

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Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
XS	AA	3,665,466	5/1972	Hibbard	343	12 R
	AB	3,812,422	5/1974	DeCarolis	324	58.5
	AC	3,829,900	9/1974	Ross	73	290 R
	AD	3,853,005	12/1974	Schendel	73	290 R
	AE	3,995,212	11/1976	Ross	324	58.5 B
	AF	4,161,731	7/1979	Barr	343	14
	AG	4,489,601	12/1984	Rao et al.	73	290 R
	AH	4,786,587	11/1988	Kuwabara	430	566
	AI	4,838,690	6/1989	Buckland et al.	356	73.1
	AJ	4,489,601	12/1984	Rao et al.	73	290 R
	AK	5,1157,337	10/1992	Neel et al.	324	632

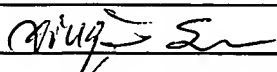
## FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Sub Class	Translation Yes No
XS	AL	EP 0 882 957 A2	9.12.98	EPO			X
XS	AM	EP 0 882 956 A2	6.6.97	EPO			X
	AN						

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

XS	AO	"Micropower Impulse Radar Technology and Applications" by J. Mast et al., Lawrence Livermore National Laboratory, UCRL-ID-130474, April 15, 1998
XS	AP	"Reflex-Radar Gauging and level measurement for liquids, interface and granular materials", KROHNE Technical Data, December 1996
XS	AQ	"Radar Level Technology Offers Accurate, Noncontact Measurements" by F. Fitch, I&CS, January 1996, pp. 27-30


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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	October 29, 2001	2857

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	BB	5,327,139	7/1994	Johnson	342	22
	BC	5,345,183	9/1994	Take	324	663
	BD	5,500,649	3/1996	Mowrey et al.	342	22
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XS	BK	5,726,578	3/1998	Hook	324	643

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	Document No.	Date	Country	Class	Sub Class	Translation Yes No
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## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

XS	BM	"Novel Methods of Measuring Impurity Levels in Liquid Tanks" by Matthias Weib, XP-000767081, <u>IEEE MTT-S Digest</u> , pp. 1651-1654, 08.06.1997
XS	BN	"Determination of Volumetric Water Content in Lossy Geophysical Media Using Time Domain Reflectometry" by B. Oswald et al., <u>Laboratory for Electromagnetic Fields and Microwave Electronics, Swiss Federal Institute of Technology</u> , pp. 2054-2057, 1997
	BO	

EXAMINER: *Amir S.*DATE CONSIDERED: *06/03/03*

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↓	CB	5,835,053	11/1998	Davis	342	22
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	CE					
	CF					
	CG					
	CH					
	CI					

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
	CJ					
	CK					
	CL					

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XS	CM	"Measurement of Dielectric Properties of Materials by Using Time Domain Reflectometry" by R. Nozaki et al., CH2735-9/90/000-0263, 1999, pp. 263-269
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	CO	

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*Wing S*

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